


<b>Search Notes</b> 	<b>Application/Control No.</b> 10759719	<b>Applicant(s)/Patent Under Reexamination</b> LEE ET AL.
	<b>Examiner</b> SHIN-HON CHEN	<b>Art Unit</b> 2131

SEARCHED			
Class	Subclass	Date	Examiner
380	256	3/28/08	S.C.

SEARCH NOTES		
Search Notes	Date	Examiner
USPAT, PGPUB, DERWENT, JPO, EPO (BRS search - see search history)	3/28/08	S.C.
NPL search (IEEE explor and Google)	3/27/08	S.C.

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner